

EAST SEARCH

1/21/03

L#	Hits	Search String	Databases
L1	26	((logic and gate and delay adj time) and rise and fall) and logical adj operation)	an USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L2	5	((logic and gate and delay adj time) and rise and fall) and logical adj operation)	an USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L3	8	((logic and gate and delay adj time) and rise and fall) and logical adj operation)	an USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L4	46970	hasegawa.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L5	956	hasegawa.in. and delay	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L6	121	(hasegawa.in. and delay) and NEC	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L7	45	(hasegawa.in. and delay) and NEC	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L1	12	((hasegawa.in. and delay) and NEC) and rise and fall	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L2	1628	delay adj calculat\$	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L3	26127	look adj3 table	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L4	74	(delay adj calculat\$) and (look adj3 table)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L5	3	((delay adj calculat\$) and (look adj3 table)) and library	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L6	473	(delay adj calculat\$) and gate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L7	67	((delay adj calculat\$) and gate) and fall and rise	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L8	38	((delay adj calculat\$) and gate) and fall and rise) and simulat\$	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L9	29	((Blinne and delay time) and logic cell) and risefall) and estimating	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	7	optimizing adj signal adj timing	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
106402	1	logic adj circuit\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	310	(logic adj circuit\$1) and (calculat\$3 adj delay)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	37	((logic adj circuit\$1) and (calculat\$3 adj delay)) and (logic\$2 adj (information or ope	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	112	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	
	96	(logic adj circuit\$1) and (comput\$5 adj delay)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	96	(logic adj circuit\$1) and (estimat\$3 adj delay)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	468	((logic adj circuit\$1) and (calculat\$3 adj delay)) or ((logic adj circuit\$1) and (computi	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	56	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	
	7	((logic adj circuit\$1) and (calculat\$3 adj delay)) or ((logic adj circuit\$1) and (calculat\$3 adj delay)) and (logic\$2 adj (information or op	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	
	11	((logic adj circuit\$1) and (calculat\$3 adj delay)) or ((logic adj circuit\$1) and (comput	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	33722	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	
	179	logic adj gate\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	47	(logic adj gate\$1) and (calculat\$3 adj delay)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	47	(logic adj gate\$1) and (comput\$5 adj delay)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	61	(logic adj gate\$1) and (estimat\$3 adj delay)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	268	((logic adj gate\$1) and (calculat\$3 adj delay)) or ((logic adj gate\$1) and (comput\$5 USPAT;	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	38	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	
	0	((logic adj gate\$1) and (calculat\$3 adj delay)) or ((logic adj gate\$1) and (comput\$ USPAT;	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	220	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	
	46	((logic adj circuit\$1) and (delay with library)) and ("connection information" or "circu	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB

0 (((logic adj circuit\$1) and (delay with library)) and ("connection information" or "circ USPAT"; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
10 (((logic adj circuit\$1) and (delay with library)) and ("connection information" or "circ USPAT"; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
220 (logic adj circuit\$1) and (delay with library)
11 ((logic adj circuit\$1) and (delay with library)) and "logic information"

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<u>Results of search set L32:(logic adj gate\$1) and ((calculat\$3 adj delay) or (comput\$5 adj delay) or (estimat\$3 adj delay)) and (logics\$2 adj (information or operation))</u>			
Document	Item	Source	Issue Date Current OR
US 20030006816 A1	Semiconductor integrated circuit device and microcomputer	20030109 327/158	
US 20020113616 A1	Semiconductor integrated circuit	20020822 326/31	
US 20020030521 A1	Semiconductor integrated circuit device and microcomputer	20020314 327/158	
US 2002008560 A1	Variable delay circuit and semiconductor integrated circuit device	20020124 327/277	
US 20010043103 A1	Semiconductor integrated circuit	20011122 327/175	
US 20010043085 A1	Semiconductor integrated circuit	20011122 326/112	
US 20010024136 A1	Semiconductor integrated circuit compensating variations of delay time	20010927 327/276	
US 20010015658 A1	Semiconductor integrated circuit device capable of producing output thereof without being influenced by other	20010823 326/104	
US 6477695 B1	Methods for designing standard cell transistor structures	20021105 716/17	
US 6477683 B1	Automated processor generation system for designing a configurable processor and method for the same	20021105 716/1	
US 6476639 B2	Semiconductor integrated circuit device capable of producing output thereof without being influenced by other	20021105 326/82	
US 6476639 B1	Semiconductor integrated circuit device and microcomputer	20021029 327/158	
US 6388483 B1	Semiconductor integrated circuit device and microcomputer	20020514 327/158	
US 6380778 B2	Semiconductor integrated circuit	20020430 327/175	
US 6304117 B1	Variable delay circuit and semiconductor integrated circuit device	20011016 327/158	
US 6301692 B1	Method for designing layout of semiconductor integrated circuit, semiconductor integrated circuit obtained by	20011009 716/10	
US 6295300 B1	Circuit and method for symmetric asynchronous interface	20010925 370/503	
US 6215345 B1	Semiconductor device for setting delay time	20010410 327/279	
US 6181184 B1	Variable delay circuit and semiconductor integrated circuit device	20010130 327/278	
US 6166577 A	Semiconductor integrated circuit device and microcomputer	20001226 327/278	
US 6097884 A	Probe points and markers for critical paths and integrated circuits	20000801 716/4	
US 5983008 A	Method for designing layout of semiconductor integrated circuit, semiconductor integrated circuit obtained by	19991109 716/6	
US 5923569 A	Method for designing layout of semiconductor integrated circuit semiconductor integrated circuit obtained by	19990713 716/7	
US 5764525 A	Method for improving the operation of a circuit through iterative substitutions and performance analyses of	c 19980609 716/18	
US 5661413 A	Processor utilizing a low voltage data circuit and a high voltage controller	19970826 326/80	
US 5619418 A	Logic gate size optimization process for an integrated circuit whereby circuit speed is improved while circuit	19970408 716/6	
US 5613062 A	Logic simulator	19970318 714/37	
US 5606567 A	Delay testing of high-performance digital components by a slow-speed tester	19970225 714/732	
US 5600583 A	Circuit and method for detecting if a sum of two multidigit numbers equals a third multidigit number prior to a	19970204 708/525	

US 5508950 A
US 5446748 A
US 5426591 A
US 5270955 A
US 5124776 A
US 5001751 A
US 4926478 A
US 4805216 A
US 3914580 A

Circuit and method for detecting if a sum of two multibit numbers equals a third multibit constant number phi 19960416 7081525
Apparatus for performing logic simulation 19950829 714814
Apparatus and method for improving the timing performance of a circuit 19950620 71616
Method of detecting arithmetic or logical computation result 19931214 7081525
Bipolar integrated circuit having a unit block structure 19920623 2571204
Mode 4 reply decoder 19910319 34245
Method and apparatus for continuously acknowledged link encrypting 19900515 705175
Method and apparatus for continuously acknowledged link encrypting 19890214 3801283
TIMING CONTROL CIRCUIT FOR ELECTRONIC FUEL INJECTION SYSTEM 19751021 37712